


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/014,536	CHO, INSIK	
	Examiner	Art Unit	
	Chris Parry	2614	

SEARCHED			
Class	Subclass	Date	Examiner
725	111	2/2/2006	CLP
725	107	2/3/2006	CLP
725	119	2/3/2006	CLP

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
See attached search history from EAST (USPAT; US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB).	2/3/2006	CLP
375/222 - (text search only - see attached search history)	2/2/2006	CLP